

#### TOSHIBA PHOTOCOUPLER PHOTO RELAY

# **TLP3213**

# MEASUREMENT INSTRUMENTS LOGIC IC TESTERS / MEMORY TESTERS BOARD TESTERS / SCANNERS

The TOSHIBA TLP3213 is a super small-outline photorelay, suitable for surface-mount assembly. The TLP3213 consists of a GaAs infrared-emitting diode optically coupled to a photo-MOS FET and housed in a 4-pin package.

Its characteristics include low OFF-state current and low output pin capacitance, enabling it to be used in high-frequency measuring instruments.

#### **Features**

• 4 pin SSOP (SSOP4) : 1.8 mm high, 1.27 mm pitch

• 1-Form-A

Peak Off-State Voltage : 40 V (MIN.)
Trigger LED Current : 4 mA (MAX.)
On-State Current : 80 mA (MAX.)

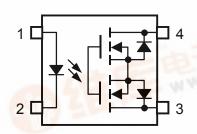
• On-State Resistance :  $35 \Omega$  (MAX.),  $25 \Omega$  (TYP.) • Output Capacitance : 1.4 pF (MAX.), 0.6 pF (TYP.)

• Isolation Voltage : 1500 Vrms (MIN.)

# 

Weight: 0.03 g

#### Pin Configuration (top view)



- 1: ANODE 2: CATHODE
- 3 : DRAIN
- 4 : DRAIN



2007-10-01

#### Absolute Maximum Ratings (Ta = 25°C)

	CHARACTERISTIC	SYMBOL	RATING	UNIT
	Forward Current	lF	50	mA
ΕĐ	Forward Current Derating (Ta ≥ 25°C)	ΔI <sub>F</sub> /°C	-0.5	mA/°C
۳	Reverse Voltage	$V_{R}$	5	V
	Junction Temperature	Tj	125	°C
~	Off-State Output Terminal Voltage	V <sub>OFF</sub>	40	V
DETECTOR	On-State Current	I <sub>ON</sub>	80	mA
	On-State Current Derating (Ta ≧ 25°C)	Δl <sub>ON</sub> /°C	-0.8	mA/°C
	Junction Temperature	Tj	125	°C
Storage Temperature Range		T <sub>stg</sub>	-40 <b>~</b> 125	°C
Operating Temperature Range		T <sub>opr</sub>	-20~85	°C
Lead	Soldering Temperature (10 s)	T <sub>sol</sub>	260	°C
Isolat	ion Voltage (AC, 1 minute, R.H. $\leq$ 60%) (NOTE1)	BVS	1500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(NOTE1): Device considered a two-terminal device: Pins 1 and, 2 shorted together, and pins 3 and 4 shorted together.

#### Caution

This device is sensitive to electrostatic discharge. When using this device, please ensure that all tools and equipment are earthed.

This device is applying super small package which is free for Moisture-Proof packing. However, the application of this device is premised on use under controlled environmental condition like as measuring instrument. It is necessary to take precautions of storage condition and operating environmental condition.

#### **Recommended Operating Conditions**

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Supply Voltage	$V_{DD}$	_	_	32	V
Forward Current	lF	10	_	30	mA
On-State Current	I <sub>ON</sub>	_	_	80	mA
Operating Temperature	T <sub>opr</sub>	25		60	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

#### **Individual Electrical Characteristics (Ta = 25°C)**

	CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
	Forward Voltage	V <sub>F</sub>	I <sub>F</sub> = 10 mA	1.0	1.15	1.3	V
LED	Reverse Current	I <sub>R</sub>	V <sub>R</sub> = 5 V			10	μА
	Capacitance	C <sub>T</sub>	V = 0, f = 1 MHz	_	15	_	pF
CTOR	Off-State Current	l <sub>OFF</sub>	V <sub>OFF</sub> = 30 V, Ta = 50°C		l	1000	pA
DETEC <sup>-</sup>	Capacitance	C <sub>OFF</sub>	V = 0, f = 100 MHz, t < 1 s		0.6	1.4	pF

# Coupled Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Trigger LED Current	I <sub>FT</sub>	I <sub>ON</sub> = 80 mA	_	_	4	mA
Return LED Current	I <sub>FC</sub>	I <sub>OFF</sub> = 10 μA	0.2	0.75	_	mA
On-State Resistance	R <sub>ON</sub>	$I_{ON} = 80 \text{ mA}, I_F = 5 \text{ mA}, t < 1 \text{ s}$	_	25	35	Ω

## Isolation Characteristics (Ta = 25°C)

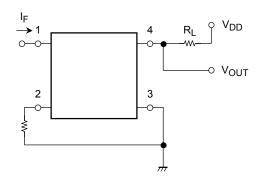
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Capacitance Input to Output	Cs	V <sub>S</sub> = 0 V, f = 1 MHz	_	0.3	_	pF
Isolation Resistance	R <sub>S</sub>	V <sub>S</sub> = 500 V, R.H. ≦ 60%	5 × 10 <sup>10</sup>	10 <sup>14</sup>	_	Ω
		AC, 1 minute	1500	_	_	Vrms
Isolation Voltage	$BV_S$	AC, 1 second (in oil)	_	3000	_	VIIIIS
		DC, 1 minute (in oil)	_	3000	_	Vdc

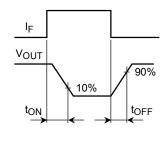
### **Switching Characteristics (Ta = 25°C)**

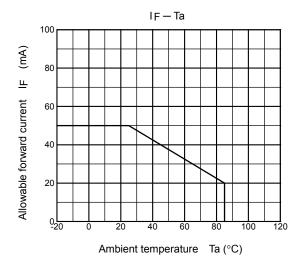
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Turn-on Time	t <sub>ON</sub>	$R_L = 200 \Omega$ (NOTE 4)	_	50	500	μS
Turn-off Time	toff	$V_{DD} = 10 \text{ V}, I_{F} = 5 \text{ mA}$	_	90	500	μδ

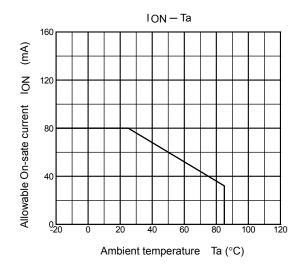
3

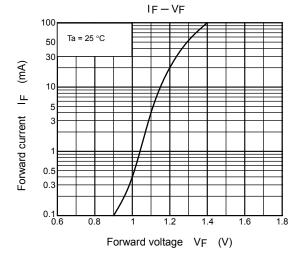
(NOTE 4): SWITCHING TIME TEST CIRCUIT

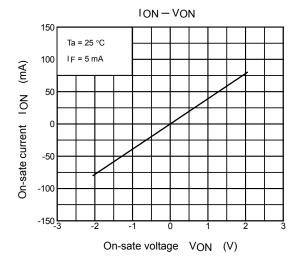


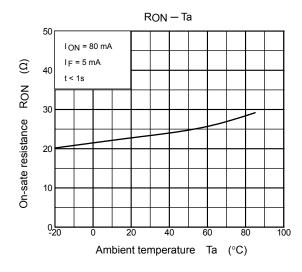


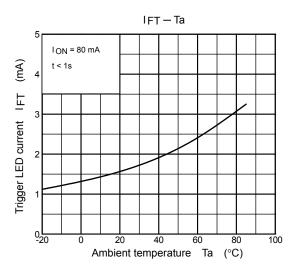


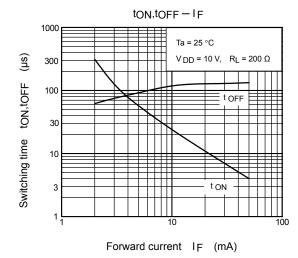


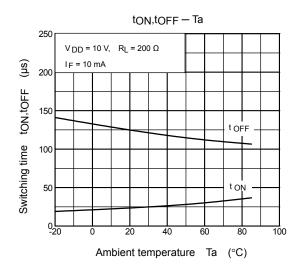


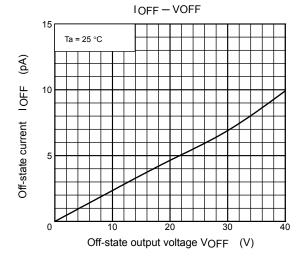


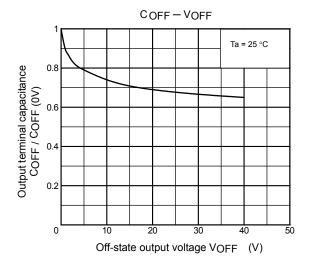




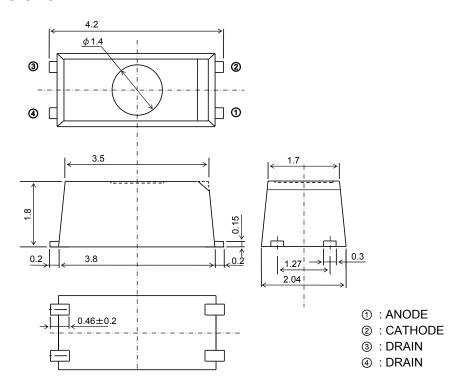








### **PACKAGE DIMENSIONS**



#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
  In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third parties.
- GaAs(Gallium Arsenide) is used in this product. The dust or vapor is harmful to the human body. Do not break, cut, crush or dissolve chemically.
- Please contact your sales representative for product-by-product details in this document regarding RoHS
  compatibility. Please use these products in this document in compliance with all applicable laws and regulations
  that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses
  occurring as a result of noncompliance with applicable laws and regulations.